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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

| | |
|--------------------------------|---|
| Product Status | Obsolete |
| Number of LABs/CLBs | 225400 |
| Number of Logic Elements/Cells | 597000 |
| Total RAM Bits | 53248000 |
| Number of I/O | 600 |
| Number of Gates | - |
| Voltage - Supply | 0.87V ~ 0.93V |
| Mounting Type | Surface Mount |
| Operating Temperature | -40°C ~ 100°C (TJ) |
| Package / Case | 1760-BBGA, FCBGA |
| Supplier Device Package | 1760-FCBGA (42.5x42.5) |
| Purchase URL | https://www.e-xfl.com/product-detail/intel/5sgxeb6r2f43i2n |

Table 1. Stratix V GX and GS Commercial and Industrial Speed Grade Offering ^{(1), (2), (3)} (Part 2 of 2)

| Transceiver Speed Grade | Core Speed Grade | | | | | | | |
|--------------------------|------------------|---------|-----|-----|---------|---------|--------------------|-----|
| | C1 | C2, C2L | C3 | C4 | I2, I2L | I3, I3L | I3YY | I4 |
| 3 GX channel—8.5 Gbps | — | Yes | Yes | Yes | — | Yes | Yes ⁽⁴⁾ | Yes |

Notes to Table 1:

- (1) C = Commercial temperature grade; I = Industrial temperature grade.
 (2) Lower number refers to faster speed grade.
 (3) C2L, I2L, and I3L speed grades are for low-power devices.
 (4) I3YY speed grades can achieve up to 10.3125 Gbps.

Table 2 lists the industrial and commercial speed grades for the Stratix V GT devices.

Table 2. Stratix V GT Commercial and Industrial Speed Grade Offering ^{(1), (2)}

| Transceiver Speed Grade | Core Speed Grade | | | |
|--|------------------|-----|-----|-----|
| | C1 | C2 | I2 | I3 |
| 2 GX channel—12.5 Gbps GT channel—28.05 Gbps | Yes | Yes | — | — |
| 3 GX channel—12.5 Gbps GT channel—25.78 Gbps | Yes | Yes | Yes | Yes |

Notes to Table 2:

- (1) C = Commercial temperature grade; I = Industrial temperature grade.
 (2) Lower number refers to faster speed grade.

Absolute Maximum Ratings

Absolute maximum ratings define the maximum operating conditions for Stratix V devices. The values are based on experiments conducted with the devices and theoretical modeling of breakdown and damage mechanisms. The functional operation of the device is not implied for these conditions.



Conditions other than those listed in Table 3 may cause permanent damage to the device. Additionally, device operation at the absolute maximum ratings for extended periods of time may have adverse effects on the device.

Table 3. Absolute Maximum Ratings for Stratix V Devices (Part 1 of 2)

| Symbol | Description | Minimum | Maximum | Unit |
|---------------------|--|---------|---------|------|
| V _{CC} | Power supply for core voltage and periphery circuitry | −0.5 | 1.35 | V |
| V _{CCPT} | Power supply for programmable power technology | −0.5 | 1.8 | V |
| V _{CCPGM} | Power supply for configuration pins | −0.5 | 3.9 | V |
| V _{CC_AUX} | Auxiliary supply for the programmable power technology | −0.5 | 3.4 | V |
| V _{CCBAT} | Battery back-up power supply for design security volatile key register | −0.5 | 3.9 | V |
| V _{CCPD} | I/O pre-driver power supply | −0.5 | 3.9 | V |
| V _{CCIO} | I/O power supply | −0.5 | 3.9 | V |

Table 8 shows the transceiver power supply voltage requirements for various conditions.

Table 8. Transceiver Power Supply Voltage Requirements

| Conditions | Core Speed Grade | VCCR_GXB & VCCT_GXB ⁽²⁾ | VCCA_GXB | VCCH_GXB | Unit |
|---|-----------------------------------|------------------------------------|----------|----------|------|
| If BOTH of the following conditions are true: <ul style="list-style-type: none"> ■ Data rate > 10.3 Gbps. ■ DFE is used. | All | 1.05 | 3.0 | 1.5 | V |
| If ANY of the following conditions are true ⁽¹⁾ : <ul style="list-style-type: none"> ■ ATX PLL is used. ■ Data rate > 6.5Gbps. ■ DFE (data rate ≤ 10.3 Gbps), AEQ, or EyeQ feature is used. | All | 1.0 | | | |
| If ALL of the following conditions are true: <ul style="list-style-type: none"> ■ ATX PLL is not used. ■ Data rate ≤ 6.5Gbps. ■ DFE, AEQ, and EyeQ are not used. | C1, C2, I2, and I3YY | 0.90 | 2.5 | | |
| | C2L, C3, C4, I2L, I3, I3L, and I4 | 0.85 | 2.5 | | |

Notes to Table 8:

- (1) Choose this power supply voltage requirement option if you plan to upgrade your design later with any of the listed conditions.
- (2) If the VCCR_GXB and VCCT_GXB supplies are set to 1.0 V or 1.05 V, they cannot be shared with the VCC core supply. If the VCCR_GXB and VCCT_GXB are set to either 0.90 V or 0.85 V, they can be shared with the VCC core supply.

DC Characteristics

This section lists the supply current, I/O pin leakage current, input pin capacitance, on-chip termination tolerance, and hot socketing specifications.

Supply Current

Supply current is the current drawn from the respective power rails used for power budgeting. Use the Excel-based Early Power Estimator (EPE) to get supply current estimates for your design because these currents vary greatly with the resources you use.



For more information about power estimation tools, refer to the *PowerPlay Early Power Estimator User Guide* and the *PowerPlay Power Analysis* chapter in the *Quartus II Handbook*.

Table 11. OCT Calibration Accuracy Specifications for Stratix V Devices ⁽¹⁾ (Part 2 of 2)

| Symbol | Description | Conditions | Calibration Accuracy | | | | Unit |
|--|--|---|----------------------|------------|----------------|------------|------|
| | | | C1 | C2,I2 | C3,I3, I3YY | C4,I4 | |
| 50-Ω R _S | Internal series termination with calibration (50-Ω setting) | V _{CCIO} = 3.0, 2.5, 1.8, 1.5, 1.2 V | ±15 | ±15 | ±15 | ±15 | % |
| 34-Ω and 40-Ω R _S | Internal series termination with calibration (34-Ω and 40-Ω setting) | V _{CCIO} = 1.5, 1.35, 1.25, 1.2 V | ±15 | ±15 | ±15 | ±15 | % |
| 48-Ω, 60-Ω, 80-Ω, and 240-Ω R _S | Internal series termination with calibration (48-Ω, 60-Ω, 80-Ω, and 240-Ω setting) | V _{CCIO} = 1.2 V | ±15 | ±15 | ±15 | ±15 | % |
| 50-Ω R _T | Internal parallel termination with calibration (50-Ω setting) | V _{CCIO} = 2.5, 1.8, 1.5, 1.2 V | -10 to +40 | -10 to +40 | -10 to +40 | -10 to +40 | % |
| 20-Ω, 30-Ω, 40-Ω, 60-Ω, and 120-Ω R _T | Internal parallel termination with calibration (20-Ω, 30-Ω, 40-Ω, 60-Ω, and 120-Ω setting) | V _{CCIO} = 1.5, 1.35, 1.25 V | -10 to +40 | -10 to +40 | -10 to +40 | -10 to +40 | % |
| 60-Ω and 120-Ω R _T | Internal parallel termination with calibration (60-Ω and 120-Ω setting) | V _{CCIO} = 1.2 | -10 to +40 | -10 to +40 | -10 to +40 | -10 to +40 | % |
| 25-Ω R _{S_left_shift} | Internal left shift series termination with calibration (25-Ω R _{S_left_shift} setting) | V _{CCIO} = 3.0, 2.5, 1.8, 1.5, 1.2 V | ±15 | ±15 | ±15 | ±15 | % |

Note to Table 11:

(1) OCT calibration accuracy is valid at the time of calibration only.

Table 12 lists the Stratix V OCT without calibration resistance tolerance to PVT changes.

Table 12. OCT Without Calibration Resistance Tolerance Specifications for Stratix V Devices (Part 1 of 2)

| Symbol | Description | Conditions | Resistance Tolerance | | | | Unit |
|-----------------------------|--|-----------------------------------|----------------------|-------|-----------------|--------|------|
| | | | C1 | C2,I2 | C3, I3, I3YY | C4, I4 | |
| 25-Ω R, 50-Ω R _S | Internal series termination without calibration (25-Ω setting) | V _{CCIO} = 3.0 and 2.5 V | ±30 | ±30 | ±40 | ±40 | % |
| 25-Ω R _S | Internal series termination without calibration (25-Ω setting) | V _{CCIO} = 1.8 and 1.5 V | ±30 | ±30 | ±40 | ±40 | % |
| 25-Ω R _S | Internal series termination without calibration (25-Ω setting) | V _{CCIO} = 1.2 V | ±35 | ±35 | ±50 | ±50 | % |

Internal Weak Pull-Up Resistor

Table 16 lists the weak pull-up resistor values for Stratix V devices.

Table 16. Internal Weak Pull-Up Resistor for Stratix V Devices ^{(1), (2)}

| Symbol | Description | V _{CCIO} Conditions (V) ⁽³⁾ | Value ⁽⁴⁾ | Unit |
|-----------------|---|---|----------------------|------|
| R _{PU} | Value of the I/O pin pull-up resistor before and during configuration, as well as user mode if you enable the programmable pull-up resistor option. | 3.0 ±5% | 25 | kΩ |
| | | 2.5 ±5% | 25 | kΩ |
| | | 1.8 ±5% | 25 | kΩ |
| | | 1.5 ±5% | 25 | kΩ |
| | | 1.35 ±5% | 25 | kΩ |
| | | 1.25 ±5% | 25 | kΩ |
| | | 1.2 ±5% | 25 | kΩ |

Notes to Table 16:

- (1) All I/O pins have an option to enable the weak pull-up resistor except the configuration, test, and JTAG pins.
- (2) The internal weak pull-down feature is only available for the JTAG TCK pin. The typical value for this internal weak pull-down resistor is approximately 25 kΩ.
- (3) The pin pull-up resistance values may be lower if an external source drives the pin higher than V_{CCIO}.
- (4) These specifications are valid with a ±10% tolerance to cover changes over PVT.

I/O Standard Specifications

Table 17 through Table 22 list the input voltage (V_{IH} and V_{IL}), output voltage (V_{OH} and V_{OL}), and current drive characteristics (I_{OH} and I_{OL}) for various I/O standards supported by Stratix V devices. These tables also show the Stratix V device family I/O standard specifications. The V_{OL} and V_{OH} values are valid at the corresponding I_{OH} and I_{OL}, respectively.

For an explanation of the terms used in Table 17 through Table 22, refer to “Glossary” on page 65. For tolerance calculations across all SSTL and HSTL I/O standards, refer to Altera knowledge base solution rd07262012_486.

Table 17. Single-Ended I/O Standards for Stratix V Devices

| I/O Standard | V _{CCIO} (V) | | | V _{IL} (V) | | V _{IH} (V) | | V _{OL} (V) | V _{OH} (V) | I _{OL} (mA) | I _{OH} (mA) |
|--------------|-----------------------|-----|-------|---------------------|-----------------------------|-----------------------------|-------------------------|-----------------------------|-----------------------------|----------------------|----------------------|
| | Min | Typ | Max | Min | Max | Min | Max | Max | Min | | |
| LVTTTL | 2.85 | 3 | 3.15 | −0.3 | 0.8 | 1.7 | 3.6 | 0.4 | 2.4 | 2 | −2 |
| LVC MOS | 2.85 | 3 | 3.15 | −0.3 | 0.8 | 1.7 | 3.6 | 0.2 | V _{CCIO} − 0.2 | 0.1 | −0.1 |
| 2.5 V | 2.375 | 2.5 | 2.625 | −0.3 | 0.7 | 1.7 | 3.6 | 0.4 | 2 | 1 | −1 |
| 1.8 V | 1.71 | 1.8 | 1.89 | −0.3 | 0.35 * V _{CCIO} | 0.65 * V _{CCIO} | V _{CCIO} + 0.3 | 0.45 | V _{CCIO} − 0.45 | 2 | −2 |
| 1.5 V | 1.425 | 1.5 | 1.575 | −0.3 | 0.35 * V _{CCIO} | 0.65 * V _{CCIO} | V _{CCIO} + 0.3 | 0.25 * V _{CCIO} | 0.75 * V _{CCIO} | 2 | −2 |
| 1.2 V | 1.14 | 1.2 | 1.26 | −0.3 | 0.35 * V _{CCIO} | 0.65 * V _{CCIO} | V _{CCIO} + 0.3 | 0.25 * V _{CCIO} | 0.75 * V _{CCIO} | 2 | −2 |

Table 19. Single-Ended SSTL, HSTL, and HSUL I/O Standards Signal Specifications for Stratix V Devices (Part 2 of 2)

| I/O Standard | $V_{IL(DC)}$ (V) | | $V_{IH(DC)}$ (V) | | $V_{IL(AC)}$ (V) | $V_{IH(AC)}$ (V) | V_{OL} (V) | V_{OH} (V) | I_{ol} (mA) | I_{oh} (mA) |
|------------------|------------------|------------------|------------------|-------------------|------------------|------------------|-------------------|-------------------|---------------|---------------|
| | Min | Max | Min | Max | Max | Min | Max | Min | | |
| HSTL-18 Class I | — | $V_{REF} - 0.1$ | $V_{REF} + 0.1$ | — | $V_{REF} - 0.2$ | $V_{REF} + 0.2$ | 0.4 | $V_{CCIO} - 0.4$ | 8 | -8 |
| HSTL-18 Class II | — | $V_{REF} - 0.1$ | $V_{REF} + 0.1$ | — | $V_{REF} - 0.2$ | $V_{REF} + 0.2$ | 0.4 | $V_{CCIO} - 0.4$ | 16 | -16 |
| HSTL-15 Class I | — | $V_{REF} - 0.1$ | $V_{REF} + 0.1$ | — | $V_{REF} - 0.2$ | $V_{REF} + 0.2$ | 0.4 | $V_{CCIO} - 0.4$ | 8 | -8 |
| HSTL-15 Class II | — | $V_{REF} - 0.1$ | $V_{REF} + 0.1$ | — | $V_{REF} - 0.2$ | $V_{REF} + 0.2$ | 0.4 | $V_{CCIO} - 0.4$ | 16 | -16 |
| HSTL-12 Class I | -0.15 | $V_{REF} - 0.08$ | $V_{REF} + 0.08$ | $V_{CCIO} + 0.15$ | $V_{REF} - 0.15$ | $V_{REF} + 0.15$ | $0.25^* V_{CCIO}$ | $0.75^* V_{CCIO}$ | 8 | -8 |
| HSTL-12 Class II | -0.15 | $V_{REF} - 0.08$ | $V_{REF} + 0.08$ | $V_{CCIO} + 0.15$ | $V_{REF} - 0.15$ | $V_{REF} + 0.15$ | $0.25^* V_{CCIO}$ | $0.75^* V_{CCIO}$ | 16 | -16 |
| HSUL-12 | — | $V_{REF} - 0.13$ | $V_{REF} + 0.13$ | — | $V_{REF} - 0.22$ | $V_{REF} + 0.22$ | $0.1^* V_{CCIO}$ | $0.9^* V_{CCIO}$ | — | — |

Table 20. Differential SSTL I/O Standards for Stratix V Devices

| I/O Standard | V_{CCIO} (V) | | | $V_{SWING(DC)}$ (V) | | $V_{X(AC)}$ (V) | | | $V_{SWING(AC)}$ (V) | |
|----------------------|----------------|------|-------|---------------------|------------------|----------------------|--------------|----------------------|---------------------------|---------------------------|
| | Min | Typ | Max | Min | Max | Min | Typ | Max | Min | Max |
| SSTL-2 Class I, II | 2.375 | 2.5 | 2.625 | 0.3 | $V_{CCIO} + 0.6$ | $V_{CCIO}/2 - 0.2$ | — | $V_{CCIO}/2 + 0.2$ | 0.62 | $V_{CCIO} + 0.6$ |
| SSTL-18 Class I, II | 1.71 | 1.8 | 1.89 | 0.25 | $V_{CCIO} + 0.6$ | $V_{CCIO}/2 - 0.175$ | — | $V_{CCIO}/2 + 0.175$ | 0.5 | $V_{CCIO} + 0.6$ |
| SSTL-15 Class I, II | 1.425 | 1.5 | 1.575 | 0.2 | (1) | $V_{CCIO}/2 - 0.15$ | — | $V_{CCIO}/2 + 0.15$ | 0.35 | — |
| SSTL-135 Class I, II | 1.283 | 1.35 | 1.45 | 0.2 | (1) | $V_{CCIO}/2 - 0.15$ | $V_{CCIO}/2$ | $V_{CCIO}/2 + 0.15$ | $2(V_{IH(AC)} - V_{REF})$ | $2(V_{IL(AC)} - V_{REF})$ |
| SSTL-125 Class I, II | 1.19 | 1.25 | 1.31 | 0.18 | (1) | $V_{CCIO}/2 - 0.15$ | $V_{CCIO}/2$ | $V_{CCIO}/2 + 0.15$ | $2(V_{IH(AC)} - V_{REF})$ | — |
| SSTL-12 Class I, II | 1.14 | 1.2 | 1.26 | 0.18 | — | $V_{REF} - 0.15$ | $V_{CCIO}/2$ | $V_{REF} + 0.15$ | -0.30 | 0.30 |

Note to Table 20:

(1) The maximum value for $V_{SWING(DC)}$ is not defined. However, each single-ended signal needs to be within the respective single-ended limits ($V_{IH(DC)}$ and $V_{IL(DC)}$).

Table 21. Differential HSTL and HSUL I/O Standards for Stratix V Devices (Part 1 of 2)

| I/O Standard | V_{CCIO} (V) | | | $V_{DIF(DC)}$ (V) | | $V_{X(AC)}$ (V) | | | $V_{CM(DC)}$ (V) | | | $V_{DIF(AC)}$ (V) | |
|---------------------|----------------|-----|-------|-------------------|-----|-----------------|-----|------|------------------|-----|------|-------------------|-----|
| | Min | Typ | Max | Min | Max | Min | Typ | Max | Min | Typ | Max | Min | Max |
| HSTL-18 Class I, II | 1.71 | 1.8 | 1.89 | 0.2 | — | 0.78 | — | 1.12 | 0.78 | — | 1.12 | 0.4 | — |
| HSTL-15 Class I, II | 1.425 | 1.5 | 1.575 | 0.2 | — | 0.68 | — | 0.9 | 0.68 | — | 0.9 | 0.4 | — |

Table 23. Transceiver Specifications for Stratix V GX and GS Devices ⁽¹⁾ (Part 2 of 7)

| Symbol/ Description | Conditions | Transceiver Speed Grade 1 | | | Transceiver Speed Grade 2 | | | Transceiver Speed Grade 3 | | | Unit |
|--|--|----------------------------------|-------------------|------|----------------------------------|-------------------|------|----------------------------------|-------------------|------|-------------|
| | | Min | Typ | Max | Min | Typ | Max | Min | Typ | Max | |
| Spread-spectrum downspread | PCIe | — | 0 to -0.5 | — | — | 0 to -0.5 | — | — | 0 to -0.5 | — | % |
| On-chip termination resistors ⁽²¹⁾ | — | — | 100 | — | — | 100 | — | — | 100 | — | Ω |
| Absolute V_{MAX} ⁽⁵⁾ | Dedicated reference clock pin | — | — | 1.6 | — | — | 1.6 | — | — | 1.6 | V |
| | RX reference clock pin | — | — | 1.2 | — | — | 1.2 | — | — | 1.2 | |
| Absolute V_{MIN} | — | -0.4 | — | — | -0.4 | — | — | -0.4 | — | — | V |
| Peak-to-peak differential input voltage | — | 200 | — | 1600 | 200 | — | 1600 | 200 | — | 1600 | mV |
| V_{ICM} (AC coupled) ⁽³⁾ | Dedicated reference clock pin | 1050/1000/900/850 ⁽²⁾ | | | 1050/1000/900/850 ⁽²⁾ | | | 1050/1000/900/850 ⁽²⁾ | | | mV |
| | RX reference clock pin | 1.0/0.9/0.85 ⁽⁴⁾ | | | 1.0/0.9/0.85 ⁽⁴⁾ | | | 1.0/0.9/0.85 ⁽⁴⁾ | | | V |
| V_{ICM} (DC coupled) | HCSL I/O standard for PCIe reference clock | 250 | — | 550 | 250 | — | 550 | 250 | — | 550 | mV |
| Transmitter REFCLK Phase Noise (622 MHz) ⁽²⁰⁾ | 100 Hz | — | — | -70 | — | — | -70 | — | — | -70 | dBc/Hz |
| | 1 kHz | — | — | -90 | — | — | -90 | — | — | -90 | dBc/Hz |
| | 10 kHz | — | — | -100 | — | — | -100 | — | — | -100 | dBc/Hz |
| | 100 kHz | — | — | -110 | — | — | -110 | — | — | -110 | dBc/Hz |
| | ≥ 1 MHz | — | — | -120 | — | — | -120 | — | — | -120 | dBc/Hz |
| Transmitter REFCLK Phase Jitter (100 MHz) ⁽¹⁷⁾ | 10 kHz to 1.5 MHz (PCIe) | — | — | 3 | — | — | 3 | — | — | 3 | ps (rms) |
| R_{REF} ⁽¹⁹⁾ | — | — | 1800 $\pm 1\%$ | — | — | 1800 $\pm 1\%$ | — | — | 1800 $\pm 1\%$ | — | Ω |
| Transceiver Clocks | | | | | | | | | | | |
| fixedclk clock frequency | PCIe Receiver Detect | — | 100 or 125 | — | — | 100 or 125 | — | — | 100 or 125 | — | MHz |

Table 23. Transceiver Specifications for Stratix V GX and GS Devices ⁽¹⁾ (Part 4 of 7)

| Symbol/ Description | Conditions | Transceiver Speed Grade 1 | | | Transceiver Speed Grade 2 | | | Transceiver Speed Grade 3 | | | Unit |
|--|--|------------------------------|---------------|-----|------------------------------|---------------|-----|------------------------------|---------------|-----|---------------|
| | | Min | Typ | Max | Min | Typ | Max | Min | Typ | Max | |
| Differential on-chip termination resistors ⁽²¹⁾ | 85- Ω setting | — | 85 \pm 30% | — | — | 85 \pm 30% | — | — | 85 \pm 30% | — | Ω |
| | 100- Ω setting | — | 100 \pm 30% | — | — | 100 \pm 30% | — | — | 100 \pm 30% | — | Ω |
| | 120- Ω setting | — | 120 \pm 30% | — | — | 120 \pm 30% | — | — | 120 \pm 30% | — | Ω |
| | 150- Ω setting | — | 150 \pm 30% | — | — | 150 \pm 30% | — | — | 150 \pm 30% | — | Ω |
| V_{ICM} (AC and DC coupled) | $V_{CCR_GXB} = 0.85\text{ V}$ or 0.9 V full bandwidth | — | 600 | — | — | 600 | — | — | 600 | — | mV |
| | $V_{CCR_GXB} = 0.85\text{ V}$ or 0.9 V half bandwidth | — | 600 | — | — | 600 | — | — | 600 | — | mV |
| | $V_{CCR_GXB} = 1.0\text{ V}/1.05\text{ V}$ full bandwidth | — | 700 | — | — | 700 | — | — | 700 | — | mV |
| | $V_{CCR_GXB} = 1.0\text{ V}$ half bandwidth | — | 750 | — | — | 750 | — | — | 750 | — | mV |
| t_{LTR} ⁽¹¹⁾ | — | — | — | 10 | — | — | 10 | — | — | 10 | μs |
| t_{LTD} ⁽¹²⁾ | — | 4 | — | — | 4 | — | — | 4 | — | — | μs |
| t_{LTD_manual} ⁽¹³⁾ | — | 4 | — | — | 4 | — | — | 4 | — | — | μs |
| $t_{LTR_LTD_manual}$ ⁽¹⁴⁾ | — | 15 | — | — | 15 | — | — | 15 | — | — | μs |
| Run Length | — | — | — | 200 | — | — | 200 | — | — | 200 | UI |
| Programmable equalization (AC Gain) ⁽¹⁰⁾ | Full bandwidth (6.25 GHz) Half bandwidth (3.125 GHz) | — | — | 16 | — | — | 16 | — | — | 16 | dB |

Table 26 shows the approximate maximum data rate using the 10G PCS.

Table 26. Stratix V 10G PCS Approximate Maximum Data Rate ⁽¹⁾

| Mode ⁽²⁾ | Transceiver Speed Grade | PMA Width | 64 | 40 | 40 | 40 | 32 | 32 |
|---------------------|-------------------------|---------------------------------------|--------------|-------|-------|------|----------|-------|
| | | PCS Width | 64 | 66/67 | 50 | 40 | 64/66/67 | 32 |
| FIFO or Register | 1 | C1, C2, C2L, I2, I2L core speed grade | 14.1 | 14.1 | 10.69 | 14.1 | 13.6 | 13.6 |
| | 2 | C1, C2, C2L, I2, I2L core speed grade | 12.5 | 12.5 | 10.69 | 12.5 | 12.5 | 12.5 |
| | | C3, I3, I3L core speed grade | 12.5 | 12.5 | 10.69 | 12.5 | 10.88 | 10.88 |
| | 3 | C1, C2, C2L, I2, I2L core speed grade | 8.5 Gbps | | | | | |
| | | C3, I3, I3L core speed grade | | | | | | |
| | | C4, I4 core speed grade | | | | | | |
| | | I3YY core speed grade | 10.3125 Gbps | | | | | |

Notes to Table 26:

- (1) The maximum data rate is in Gbps.
- (2) The Phase Compensation FIFO can be configured in FIFO mode or register mode. In the FIFO mode, the pointers are not fixed, and the latency can vary. In the register mode the pointers are fixed for low latency.

Table 28. Transceiver Specifications for Stratix V GT Devices (Part 5 of 5) ⁽¹⁾

| Symbol/ Description | Conditions | Transceiver Speed Grade 2 | | | Transceiver Speed Grade 3 | | | Unit |
|---------------------------------|------------|------------------------------|-----|-----|------------------------------|-----|-----|------|
| | | Min | Typ | Max | Min | Typ | Max | |
| t_{pll_lock} ⁽¹⁴⁾ | — | — | — | 10 | — | — | 10 | μs |

Notes to Table 28:

- (1) Speed grades shown refer to the PMA Speed Grade in the device ordering code. The maximum data rate could be restricted by the Core/PCS speed grade. Contact your Altera Sales Representative for the maximum data rate specifications in each speed grade combination offered. For more information about device ordering codes, refer to the *Stratix V Device Overview*.
- (2) The reference clock common mode voltage is equal to the VCCR_GXB power supply level.
- (3) The device cannot tolerate prolonged operation at this absolute maximum.
- (4) The differential eye opening specification at the receiver input pins assumes that receiver equalization is disabled. If you enable receiver equalization, the receiver circuitry can tolerate a lower minimum eye opening, depending on the equalization level.
- (5) Refer to Figure 5 for the GT channel AC gain curves. The total effective AC gain is the AC gain minus the DC gain.
- (6) Refer to Figure 6 for the GT channel DC gain curves.
- (7) CFP2 optical modules require the host interface to have the receiver data pins differentially terminated with 100 Ω. The internal OCT feature is available after the Stratix V FPGA configuration is completed. Altera recommends that FPGA configuration is completed before inserting the optical module. Otherwise, minimize unnecessary removal and insertion with unconfigured devices.
- (8) Specifications for this parameter are the same as for Stratix V GX and GS devices. See Table 23 for specifications.
- (9) t_{LTR} is the time required for the receive CDR to lock to the input reference clock frequency after coming out of reset.
- (10) t_{LTD} is time required for the receiver CDR to start recovering valid data after the $rx_is_lockedto\ data$ signal goes high.
- (11) t_{LTD_manual} is the time required for the receiver CDR to start recovering valid data after the $rx_is_lockedto\ data$ signal goes high when the CDR is functioning in the manual mode.
- (12) $t_{LTR_LTD_manual}$ is the time the receiver CDR must be kept in lock to reference (LTR) mode after the $rx_is_lockedto\ ref$ signal goes high when the CDR is functioning in the manual mode.
- (13) $tp11_powerdown$ is the PLL powerdown minimum pulse width.
- (14) $tp11_lock$ is the time required for the transmitter CMU/ATX PLL to lock to the input reference clock frequency after coming out of reset.
- (15) To calculate the REFCLK rms phase jitter requirement for PCIe at reference clock frequencies other than 100 MHz, use the following formula:
REFCLK rms phase jitter at f(MHz) = REFCLK rms phase jitter at 100 MHz × 100/f.
- (16) The maximum peak to peak differential input voltage V_{ID} after device configuration is equal to $4 \times (\text{absolute } V_{MAX} \text{ for receiver pin} - V_{ICM})$.
- (17) For ES devices, RREF is 2000 Ω ±1%.
- (18) To calculate the REFCLK phase noise requirement at frequencies other than 622 MHz, use the following formula: REFCLK phase noise at f(MHz) = REFCLK phase noise at 622 MHz + 20*log(f/622).
- (19) SFP/+ optical modules require the host interface to have RD+/- differentially terminated with 100 Ω. The internal OCT feature is available after the Stratix V FPGA configuration is completed. Altera recommends that FPGA configuration is completed before inserting the optical module. Otherwise, minimize unnecessary removal and insertion with unconfigured devices.
- (20) Refer to Figure 4.
- (21) For oversampling design to support data rates less than the minimum specification, the CDR needs to be in LTR mode only.
- (22) This supply follows VCCR_GXB for both GX and GT channels.
- (23) When you use fPLL as a TXPLL of the transceiver.

Table 29 shows the V_{OD} settings for the GT channel.

Table 29. Typical V_{OD} Setting for GT Channel, TX Termination = 100 Ω

| Symbol | V_{OD} Setting | V_{OD} Value (mV) |
|---|------------------|---------------------|
| V_{OD} differential peak to peak typical ⁽¹⁾ | 0 | 0 |
| | 1 | 200 |
| | 2 | 400 |
| | 3 | 600 |
| | 4 | 800 |
| | 5 | 1000 |

Note:

(1) Refer to Figure 4.

PLL Specifications

Table 31 lists the Stratix V PLL specifications when operating in both the commercial junction temperature range (0° to 85°C) and the industrial junction temperature range (–40° to 100°C).

Table 31. PLL Specifications for Stratix V Devices (Part 1 of 3)

| Symbol | Parameter | Min | Typ | Max | Unit |
|--------------------------|--|-----|-----|--------------------|------|
| f_{IN} | Input clock frequency (C1, C2, C2L, I2, and I2L speed grades) | 5 | — | 800 ⁽¹⁾ | MHz |
| | Input clock frequency (C3, I3, I3L, and I3YY speed grades) | 5 | — | 800 ⁽¹⁾ | MHz |
| | Input clock frequency (C4, I4 speed grades) | 5 | — | 650 ⁽¹⁾ | MHz |
| f_{INPFD} | Input frequency to the PFD | 5 | — | 325 | MHz |
| f_{FINPFD} | Fractional Input clock frequency to the PFD | 50 | — | 160 | MHz |
| f_{VCO} ⁽⁹⁾ | PLL VCO operating range (C1, C2, C2L, I2, I2L speed grades) | 600 | — | 1600 | MHz |
| | PLL VCO operating range (C3, I3, I3L, I3YY speed grades) | 600 | — | 1600 | MHz |
| | PLL VCO operating range (C4, I4 speed grades) | 600 | — | 1300 | MHz |
| $t_{EINDUTY}$ | Input clock or external feedback clock input duty cycle | 40 | — | 60 | % |
| f_{OUT} | Output frequency for an internal global or regional clock (C1, C2, C2L, I2, I2L speed grades) | — | — | 717 ⁽²⁾ | MHz |
| | Output frequency for an internal global or regional clock (C3, I3, I3L speed grades) | — | — | 650 ⁽²⁾ | MHz |
| | Output frequency for an internal global or regional clock (C4, I4 speed grades) | — | — | 580 ⁽²⁾ | MHz |
| f_{OUT_EXT} | Output frequency for an external clock output (C1, C2, C2L, I2, I2L speed grades) | — | — | 800 ⁽²⁾ | MHz |
| | Output frequency for an external clock output (C3, I3, I3L speed grades) | — | — | 667 ⁽²⁾ | MHz |
| | Output frequency for an external clock output (C4, I4 speed grades) | — | — | 553 ⁽²⁾ | MHz |
| $t_{OUTDUTY}$ | Duty cycle for a dedicated external clock output (when set to 50%) | 45 | 50 | 55 | % |
| t_{FCOMP} | External feedback clock compensation time | — | — | 10 | ns |
| $f_{DYCONFIGCLK}$ | Dynamic Configuration Clock used for <code>mgmt_clk</code> and <code>scanclk</code> | — | — | 100 | MHz |
| t_{LOCK} | Time required to lock from the end-of-device configuration or deassertion of <code>areset</code> | — | — | 1 | ms |
| t_{DLOCK} | Time required to lock dynamically (after switchover or reconfiguring any non-post-scale counters/delays) | — | — | 1 | ms |
| f_{CLBW} | PLL closed-loop low bandwidth | — | 0.3 | — | MHz |
| | PLL closed-loop medium bandwidth | — | 1.5 | — | MHz |
| | PLL closed-loop high bandwidth ⁽⁷⁾ | — | 4 | — | MHz |
| t_{PLL_PSERR} | Accuracy of PLL phase shift | — | — | ±50 | ps |
| t_{ARESET} | Minimum pulse width on the <code>areset</code> signal | 10 | — | — | ns |

Table 31. PLL Specifications for Stratix V Devices (Part 2 of 3)

| Symbol | Parameter | Min | Typ | Max | Unit |
|--|--|------|---------|--|-----------|
| t_{INCCJ} ^{(3), (4)} | Input clock cycle-to-cycle jitter ($f_{\text{REF}} \geq 100$ MHz) | — | — | 0.15 | UI (p-p) |
| | Input clock cycle-to-cycle jitter ($f_{\text{REF}} < 100$ MHz) | −750 | — | +750 | ps (p-p) |
| $t_{\text{OUTPJ_DC}}$ ⁽⁵⁾ | Period Jitter for dedicated clock output ($f_{\text{OUT}} \geq 100$ MHz) | — | — | 175 ⁽¹⁾ | ps (p-p) |
| | Period Jitter for dedicated clock output ($f_{\text{OUT}} < 100$ MHz) | — | — | 17.5 ⁽¹⁾ | mUI (p-p) |
| $t_{\text{FOUTPJ_DC}}$ ⁽⁵⁾ | Period Jitter for dedicated clock output in fractional PLL ($f_{\text{OUT}} \geq 100$ MHz) | — | — | 250 ⁽¹¹⁾ , 175 ⁽¹²⁾ | ps (p-p) |
| | Period Jitter for dedicated clock output in fractional PLL ($f_{\text{OUT}} < 100$ MHz) | — | — | 25 ⁽¹¹⁾ , 17.5 ⁽¹²⁾ | mUI (p-p) |
| $t_{\text{OUTCCJ_DC}}$ ⁽⁵⁾ | Cycle-to-Cycle Jitter for a dedicated clock output ($f_{\text{OUT}} \geq 100$ MHz) | — | — | 175 | ps (p-p) |
| | Cycle-to-Cycle Jitter for a dedicated clock output ($f_{\text{OUT}} < 100$ MHz) | — | — | 17.5 | mUI (p-p) |
| $t_{\text{FOUTCCJ_DC}}$ ⁽⁵⁾ | Cycle-to-cycle Jitter for a dedicated clock output in fractional PLL ($f_{\text{OUT}} \geq 100$ MHz) | — | — | 250 ⁽¹¹⁾ , 175 ⁽¹²⁾ | ps (p-p) |
| | Cycle-to-cycle Jitter for a dedicated clock output in fractional PLL ($f_{\text{OUT}} < 100$ MHz)+ | — | — | 25 ⁽¹¹⁾ , 17.5 ⁽¹²⁾ | mUI (p-p) |
| $t_{\text{OUTPJ_IO}}$ ^{(5), (8)} | Period Jitter for a clock output on a regular I/O in integer PLL ($f_{\text{OUT}} \geq 100$ MHz) | — | — | 600 | ps (p-p) |
| | Period Jitter for a clock output on a regular I/O ($f_{\text{OUT}} < 100$ MHz) | — | — | 60 | mUI (p-p) |
| $t_{\text{FOUTPJ_IO}}$ ^{(5), (8), (11)} | Period Jitter for a clock output on a regular I/O in fractional PLL ($f_{\text{OUT}} \geq 100$ MHz) | — | — | 600 ⁽¹⁰⁾ | ps (p-p) |
| | Period Jitter for a clock output on a regular I/O in fractional PLL ($f_{\text{OUT}} < 100$ MHz) | — | — | 60 ⁽¹⁰⁾ | mUI (p-p) |
| $t_{\text{OUTCCJ_IO}}$ ^{(5), (8)} | Cycle-to-cycle Jitter for a clock output on a regular I/O in integer PLL ($f_{\text{OUT}} \geq 100$ MHz) | — | — | 600 | ps (p-p) |
| | Cycle-to-cycle Jitter for a clock output on a regular I/O in integer PLL ($f_{\text{OUT}} < 100$ MHz) | — | — | 60 ⁽¹⁰⁾ | mUI (p-p) |
| $t_{\text{FOUTCCJ_IO}}$ ^{(5), (8), (11)} | Cycle-to-cycle Jitter for a clock output on a regular I/O in fractional PLL ($f_{\text{OUT}} \geq 100$ MHz) | — | — | 600 ⁽¹⁰⁾ | ps (p-p) |
| | Cycle-to-cycle Jitter for a clock output on a regular I/O in fractional PLL ($f_{\text{OUT}} < 100$ MHz) | — | — | 60 | mUI (p-p) |
| $t_{\text{CASC_OUTPJ_DC}}$ ^{(5), (6)} | Period Jitter for a dedicated clock output in cascaded PLLs ($f_{\text{OUT}} \geq 100$ MHz) | — | — | 175 | ps (p-p) |
| | Period Jitter for a dedicated clock output in cascaded PLLs ($f_{\text{OUT}} < 100$ MHz) | — | — | 17.5 | mUI (p-p) |
| f_{DRIFT} | Frequency drift after PFDENA is disabled for a duration of 100 μ s | — | — | ± 10 | % |
| dK_{BIT} | Bit number of Delta Sigma Modulator (DSM) | 8 | 24 | 32 | Bits |
| k_{VALUE} | Numerator of Fraction | 128 | 8388608 | 2147483648 | — |

Periphery Performance

This section describes periphery performance, including high-speed I/O and external memory interface.

I/O performance supports several system interfaces, such as the **LVDS** high-speed I/O interface, external memory interface, and the **PCI/PCI-X** bus interface.

General-purpose I/O standards such as 3.3-, 2.5-, 1.8-, and 1.5-**LVTTL/LVCMOS** are capable of a typical 167 MHz and 1.2-**LVCMOS** at 100 MHz interfacing frequency with a 10 pF load.



The actual achievable frequency depends on design- and system-specific factors. Ensure proper timing closure in your design and perform HSPICE/IBIS simulations based on your specific design and system setup to determine the maximum achievable frequency in your system.

High-Speed I/O Specification

Table 36 lists high-speed I/O timing for Stratix V devices.

Table 36. High-Speed I/O Specifications for Stratix V Devices ⁽¹⁾, ⁽²⁾ (Part 1 of 4)

| Symbol | Conditions | C1 | | | C2, C2L, I2, I2L | | | C3, I3, I3L, I3YY | | | C4,I4 | | | Unit |
|--|--|-----|-----|-----|------------------|-----|-----|-------------------|-----|--------------------|-------|-----|--------------------|------|
| | | Min | Typ | Max | Min | Typ | Max | Min | Typ | Max | Min | Typ | Max | |
| $f_{\text{HCLK_in}}$ (input clock frequency) True Differential I/O Standards | Clock boost factor $W = 1$ to 40 ⁽⁴⁾ | 5 | — | 800 | 5 | — | 800 | 5 | — | 625 | 5 | — | 525 | MHz |
| $f_{\text{HCLK_in}}$ (input clock frequency) Single Ended I/O Standards ⁽³⁾ | Clock boost factor $W = 1$ to 40 ⁽⁴⁾ | 5 | — | 800 | 5 | — | 800 | 5 | — | 625 | 5 | — | 525 | MHz |
| $f_{\text{HCLK_in}}$ (input clock frequency) Single Ended I/O Standards | Clock boost factor $W = 1$ to 40 ⁽⁴⁾ | 5 | — | 520 | 5 | — | 520 | 5 | — | 420 | 5 | — | 420 | MHz |
| $f_{\text{HCLK_OUT}}$ (output clock frequency) | — | 5 | — | 800 | 5 | — | 800 | 5 | — | 625 ⁽⁵⁾ | 5 | — | 525 ⁽⁵⁾ | MHz |

Table 36. High-Speed I/O Specifications for Stratix V Devices ^{(1), (2)} (Part 2 of 4)

| Symbol | Conditions | C1 | | | C2, C2L, I2, I2L | | | C3, I3, I3L, I3YY | | | C4,I4 | | | Unit |
|--|---|-----|-----|------|------------------|-----|------|-------------------|-----|------|-------|-----|------|------|
| | | Min | Typ | Max | Min | Typ | Max | Min | Typ | Max | Min | Typ | Max | |
| Transmitter | | | | | | | | | | | | | | |
| True Differential I/O Standards - f _{HSDR} (data rate) | SERDES factor J = 3 to 10 ^{(9), (11), (12), (13), (14), (15), (16)} | (6) | — | 1600 | (6) | — | 1434 | (6) | — | 1250 | (6) | — | 1050 | Mbps |
| | SERDES factor J ≥ 4 LVDS TX with DPA ^{(12), (14), (15), (16)} | (6) | — | 1600 | (6) | — | 1600 | (6) | — | 1600 | (6) | — | 1250 | Mbps |
| | SERDES factor J = 2, uses DDR Registers | (6) | — | (7) | (6) | — | (7) | (6) | — | (7) | (6) | — | (7) | Mbps |
| | SERDES factor J = 1, uses SDR Register | (6) | — | (7) | (6) | — | (7) | (6) | — | (7) | (6) | — | (7) | Mbps |
| Emulated Differential I/O Standards with Three External Output Resistor Networks - f _{HSDR} (data rate) ⁽¹⁰⁾ | SERDES factor J = 4 to 10 ⁽¹⁷⁾ | (6) | — | 1100 | (6) | — | 1100 | (6) | — | 840 | (6) | — | 840 | Mbps |
| t _{x Jitter} - True Differential I/O Standards | Total Jitter for Data Rate 600 Mbps - 1.25 Gbps | — | — | 160 | — | — | 160 | — | — | 160 | — | — | 160 | ps |
| | Total Jitter for Data Rate < 600 Mbps | — | — | 0.1 | — | — | 0.1 | — | — | 0.1 | — | — | 0.1 | UI |
| t _{x Jitter} - Emulated Differential I/O Standards with Three External Output Resistor Network | Total Jitter for Data Rate 600 Mbps - 1.25 Gbps | — | — | 300 | — | — | 300 | — | — | 300 | — | — | 325 | ps |
| | Total Jitter for Data Rate < 600 Mbps | — | — | 0.2 | — | — | 0.2 | — | — | 0.2 | — | — | 0.25 | UI |

Table 38. LVDS Soft-CDR/DPA Sinusoidal Jitter Mask Values for a Data Rate ≥ 1.25 Gbps

| Jitter Frequency (Hz) | | Sinusoidal Jitter (UI) |
|-----------------------|------------|------------------------|
| F1 | 10,000 | 25.000 |
| F2 | 17,565 | 25.000 |
| F3 | 1,493,000 | 0.350 |
| F4 | 50,000,000 | 0.350 |

Figure 9 shows the LVDS soft-CDR/DPA sinusoidal jitter tolerance specification for a data rate < 1.25 Gbps.

Figure 9. LVDS Soft-CDR/DPA Sinusoidal Jitter Tolerance Specification for a Data Rate < 1.25 Gbps

DLL Range, DQS Logic Block, and Memory Output Clock Jitter Specifications

Table 39 lists the DLL range specification for Stratix V devices. The DLL is always in 8-tap mode in Stratix V devices.

Table 39. DLL Range Specifications for Stratix V Devices ⁽¹⁾

| C1 | C2, C2L, I2, I2L | C3, I3, I3L, I3YY | C4,I4 | Unit |
|---------|------------------|-------------------|---------|------|
| 300-933 | 300-933 | 300-890 | 300-890 | MHz |

Note to Table 39:

- (1) Stratix V devices support memory interface frequencies lower than 300 MHz, although the reference clock that feeds the DLL must be at least 300 MHz. To support interfaces below 300 MHz, multiply the reference clock feeding the DLL to ensure the frequency is within the supported range of the DLL.

Table 40 lists the DQS phase offset delay per stage for Stratix V devices.

Table 40. DQS Phase Offset Delay Per Setting for Stratix V Devices ^{(1), (2)} (Part 1 of 2)

| Speed Grade | Min | Max | Unit |
|------------------|-----|-----|------|
| C1 | 8 | 14 | ps |
| C2, C2L, I2, I2L | 8 | 14 | ps |
| C3,I3, I3L, I3YY | 8 | 15 | ps |

Duty Cycle Distortion (DCD) Specifications

Table 44 lists the worst-case DCD for Stratix V devices.

Table 44. Worst-Case DCD on Stratix V I/O Pins ⁽¹⁾

| Symbol | C1 | | C2, C2L, I2, I2L | | C3, I3, I3L, I3YY | | C4, I4 | | Unit |
|-------------------|-----|-----|------------------|-----|-------------------|-----|--------|-----|------|
| | Min | Max | Min | Max | Min | Max | Min | Max | |
| Output Duty Cycle | 45 | 55 | 45 | 55 | 45 | 55 | 45 | 55 | % |

Note to Table 44:

(1) The DCD numbers do not cover the core clock network.

Configuration Specification

POR Delay Specification

Power-on reset (POR) delay is defined as the delay between the time when all the power supplies monitored by the POR circuitry reach the minimum recommended operating voltage to the time when the nSTATUS is released high and your device is ready to begin configuration.



For more information about the POR delay, refer to the *Hot Socketing and Power-On Reset in Stratix V Devices* chapter.

Table 45 lists the fast and standard POR delay specification.

Table 45. Fast and Standard POR Delay Specification ⁽¹⁾

| POR Delay | Minimum | Maximum |
|-----------|---------|---------|
| Fast | 4 ms | 12 ms |
| Standard | 100 ms | 300 ms |

Note to Table 45:

(1) You can select the POR delay based on the MSEL settings as described in the MSEL Pin Settings section of the “Configuration, Design Security, and Remote System Upgrades in Stratix V Devices” chapter.

JTAG Configuration Specifications

Table 46 lists the JTAG timing parameters and values for Stratix V devices.

Table 46. JTAG Timing Parameters and Values for Stratix V Devices

| Symbol | Description | Min | Max | Unit |
|-------------------------|------------------------------------|-----|-----|------|
| t _{JCP} | TCK clock period ⁽²⁾ | 30 | — | ns |
| t _{JCP} | TCK clock period ⁽²⁾ | 167 | — | ns |
| t _{JCH} | TCK clock high time ⁽²⁾ | 14 | — | ns |
| t _{JCL} | TCK clock low time ⁽²⁾ | 14 | — | ns |
| t _{JPSU (TDI)} | TDI JTAG port setup time | 2 | — | ns |
| t _{JPSU (TMS)} | TMS JTAG port setup time | 3 | — | ns |

Table 49. DCLK-to-DATA[] Ratio ⁽¹⁾ (Part 2 of 2)

| Configuration Scheme | Decompression | Design Security | DCLK-to-DATA[] Ratio |
|----------------------|---------------|-----------------|----------------------|
| FPP ×32 | Disabled | Disabled | 1 |
| | Disabled | Enabled | 4 |
| | Enabled | Disabled | 8 |
| | Enabled | Enabled | 8 |

Note to Table 49:

- (1) Depending on the DCLK-to-DATA[] ratio, the host must send a DCLK frequency that is r times the data rate in bytes per second (Bps), or words per second (Wps). For example, in FPP ×16 when the DCLK-to-DATA[] ratio is 2, the DCLK frequency must be 2 times the data rate in Wps. Stratix V devices use the additional clock cycles to decrypt and decompress the configuration data.



If the DCLK-to-DATA[] ratio is greater than 1, at the end of configuration, you can only stop the DCLK (DCLK-to-DATA[] ratio – 1) clock cycles after the last data is latched into the Stratix V device.

Figure 11 shows the configuration interface connections between the Stratix V device and a MAX II or MAX V device for single device configuration.

Figure 11. Single Device FPP Configuration Using an External Host**Notes to Figure 11:**

- (1) Connect the resistor to a supply that provides an acceptable input signal for the Stratix V device. V_{CCPGM} must be high enough to meet the V_{IH} specification of the I/O on the device and the external host. Altera recommends powering up all configuration system I/Os with V_{CCPGM} .
- (2) You can leave the nCEO pin unconnected or use it as a user I/O pin when it does not feed another device's nCE pin.
- (3) The MSEL pin settings vary for different data width, configuration voltage standards, and POR delay. To connect MSEL, refer to the MSEL Pin Settings section of the "Configuration, Design Security, and Remote System Upgrades in Stratix V Devices" chapter.
- (4) If you use FPP ×8, use DATA[7..0]. If you use FPP ×16, use DATA[15..0].

Table 53. AS Timing Parameters for AS ×1 and AS ×4 Configurations in Stratix V Devices ^{(1), (2)} (Part 2 of 2)

| Symbol | Parameter | Minimum | Maximum | Units |
|--------------|---|--|---------|-------|
| t_{CD2UM} | CONF_DONE high to user mode ⁽³⁾ | 175 | 437 | μs |
| t_{CD2CU} | CONF_DONE high to CLKUSR enabled | 4 × maximum DCLK period | — | — |
| t_{CD2UMC} | CONF_DONE high to user mode with CLKUSR option on | $t_{CD2CU} + (8576 \times \text{CLKUSR period})$ | — | — |

Notes to Table 53:

- (1) The minimum and maximum numbers apply only if you choose the internal oscillator as the clock source for initializing the device.
- (2) t_{CF2CD} , t_{CF2ST0} , t_{CFG} , t_{STATUS} , and t_{CF2ST1} timing parameters are identical to the timing parameters for PS mode listed in Table 54 on page 63.
- (3) To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on this pin, refer to the Initialization section of the “Configuration, Design Security, and Remote System Upgrades in Stratix V Devices” chapter.

Passive Serial Configuration Timing

Figure 15 shows the timing waveform for a passive serial (PS) configuration when using a MAX II device, MAX V device, or microprocessor as an external host.

Figure 15. PS Configuration Timing Waveform ⁽¹⁾**Notes to Figure 15:**

- (1) The beginning of this waveform shows the device in user mode. In user mode, nCONFIG, nSTATUS, and CONF_DONE are at logic high levels. When nCONFIG is pulled low, a reconfiguration cycle begins.
- (2) After power-up, the Stratix V device holds nSTATUS low for the time of the POR delay.
- (3) After power-up, before and during configuration, CONF_DONE is low.
- (4) Do not leave DCLK floating after configuration. You can drive it high or low, whichever is more convenient.
- (5) DATA0 is available as a user I/O pin after configuration. The state of this pin depends on the dual-purpose pin settings in the **Device and Pins Option**.
- (6) To ensure a successful configuration, send the entire configuration data to the Stratix V device. CONF_DONE is released high after the Stratix V device receives all the configuration data successfully. After CONF_DONE goes high, send two additional falling edges on DCLK to begin initialization and enter user mode.
- (7) After the option bit to enable the INIT_DONE pin is configured into the device, the INIT_DONE goes low.

Table 54 lists the PS configuration timing parameters for Stratix V devices.

Table 54. PS Timing Parameters for Stratix V Devices

| Symbol | Parameter | Minimum | Maximum | Units |
|----------------------------|---|---|----------------------|---------|
| t_{CF2CD} | nCONFIG low to CONF_DONE low | — | 600 | ns |
| t_{CF2ST0} | nCONFIG low to nSTATUS low | — | 600 | ns |
| t_{CFG} | nCONFIG low pulse width | 2 | — | μ s |
| t_{STATUS} | nSTATUS low pulse width | 268 | 1,506 ⁽¹⁾ | μ s |
| t_{CF2ST1} | nCONFIG high to nSTATUS high | — | 1,506 ⁽²⁾ | μ s |
| t_{CF2CK} ⁽⁵⁾ | nCONFIG high to first rising edge on DCLK | 1,506 | — | μ s |
| t_{ST2CK} ⁽⁵⁾ | nSTATUS high to first rising edge of DCLK | 2 | — | μ s |
| t_{DSU} | DATA [] setup time before rising edge on DCLK | 5.5 | — | ns |
| t_{DH} | DATA [] hold time after rising edge on DCLK | 0 | — | ns |
| t_{CH} | DCLK high time | $0.45 \times 1/f_{MAX}$ | — | s |
| t_{CL} | DCLK low time | $0.45 \times 1/f_{MAX}$ | — | s |
| t_{CLK} | DCLK period | $1/f_{MAX}$ | — | s |
| f_{MAX} | DCLK frequency | — | 125 | MHz |
| t_{CD2UM} | CONF_DONE high to user mode ⁽³⁾ | 175 | 437 | μ s |
| t_{CD2CU} | CONF_DONE high to CLKUSR enabled | 4 × maximum DCLK period | — | — |
| t_{CD2UMC} | CONF_DONE high to user mode with CLKUSR option on | $t_{CD2CU} + (8576 \times \text{CLKUSR period})$ ⁽⁴⁾ | — | — |

Notes to Table 54:

- (1) This value is applicable if you do not delay configuration by extending the nCONFIG or nSTATUS low pulse width.
- (2) This value is applicable if you do not delay configuration by externally holding the nSTATUS low.
- (3) The minimum and maximum numbers apply only if you choose the internal oscillator as the clock source for initializing the device.
- (4) To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on these pins, refer to the “Initialization” section.
- (5) If nSTATUS is monitored, follow the t_{ST2CK} specification. If nSTATUS is not monitored, follow the t_{CF2CK} specification.

Initialization

Table 55 lists the initialization clock source option, the applicable configuration schemes, and the maximum frequency.

Table 55. Initialization Clock Source Option and the Maximum Frequency

| Initialization Clock Source | Configuration Schemes | Maximum Frequency | Minimum Number of Clock Cycles ⁽¹⁾ |
|-----------------------------|----------------------------|-------------------|---|
| Internal Oscillator | AS, PS, FPP | 12.5 MHz | 8576 |
| CLKUSR | AS, PS, FPP ⁽²⁾ | 125 MHz | |
| DCLK | PS, FPP | 125 MHz | |

Notes to Table 55:

- (1) The minimum number of clock cycles required for device initialization.
- (2) To enable CLKUSR as the initialization clock source, turn on the **Enable user-supplied start-up clock (CLKUSR)** option in the Quartus II software from the **General** panel of the **Device and Pin Options** dialog box.

Document Revision History

Table 61 lists the revision history for this chapter.

Table 61. Document Revision History (Part 1 of 3)

| Date | Version | Changes |
|---------------|---------|---|
| June 2018 | 3.9 | <ul style="list-style-type: none"> ■ Added the “Stratix V Device Overshoot Duration” figure. |
| April 2017 | 3.8 | <ul style="list-style-type: none"> ■ Added a footnote to the “High-Speed I/O Specifications for Stratix V Devices” table. ■ Changed the minimum value for t_{CD2UMC} in the “PS Timing Parameters for Stratix V Devices” table. ■ Changed the condition for $100\text{-}\Omega$ R_D in the “OCT Without Calibration Resistance Tolerance Specifications for Stratix V Devices” table. ■ Changed the minimum value for t_{CD2UMC} in the “AS Timing Parameters for AS ‘1 and AS ‘4 Configurations in Stratix V Devices” table ■ Changed the minimum value for t_{CD2UMC} in the “FPP Timing Parameters for Stratix V Devices When the DCLK-to-DATA[] Ratio is >1” table. ■ Changed the minimum value for t_{CD2UMC} in the “FPP Timing Parameters for Stratix V Devices When the DCLK-to-DATA[] Ratio is >1” table. ■ Changed the minimum number of clock cycles value in the “Initialization Clock Source Option and the Maximum Frequency” table. |
| June 2016 | 3.7 | <ul style="list-style-type: none"> ■ Added the V_{ID} minimum specification for LVPECL in the “Differential I/O Standard Specifications for Stratix V Devices” table ■ Added the I_{OUT} specification to the “Absolute Maximum Ratings for Stratix V Devices” table. |
| December 2015 | 3.6 | <ul style="list-style-type: none"> ■ Added a footnote to the “High-Speed I/O Specifications for Stratix V Devices” table. |
| December 2015 | 3.5 | <ul style="list-style-type: none"> ■ Changed the transmitter, receiver, and ATX PLL data rate specifications in the “Transceiver Specifications for Stratix V GX and GS Devices” table. ■ Changed the configuration .rbf sizes in the “Uncompressed .rbf Sizes for Stratix V Devices” table. |
| July 2015 | 3.4 | <ul style="list-style-type: none"> ■ Changed the data rate specification for transceiver speed grade 3 in the following tables: <ul style="list-style-type: none"> ■ “Transceiver Specifications for Stratix V GX and GS Devices” ■ “Stratix V Standard PCS Approximate Maximum Date Rate” ■ “Stratix V 10G PCS Approximate Maximum Data Rate” ■ Changed the conditions for reference clock rise and fall time, and added a note to the “Transceiver Specifications for Stratix V GX and GS Devices” table. ■ Added a note to the “Minimum differential eye opening at receiver serial input pins” specification in the “Transceiver Specifications for Stratix V GX and GS Devices” table. ■ Changed the t_{CO} maximum value in the “AS Timing Parameters for AS ‘1 and AS ‘4 Configurations in Stratix V Devices” table. ■ Removed the CDR ppm tolerance specification from the “Transceiver Specifications for Stratix V GX and GS Devices” table. |